

Action = Pattern Data * Timing Data (Limited by TimeSet) * Waveset * Drive

Figure 1

BEST AVAILABLE COPY

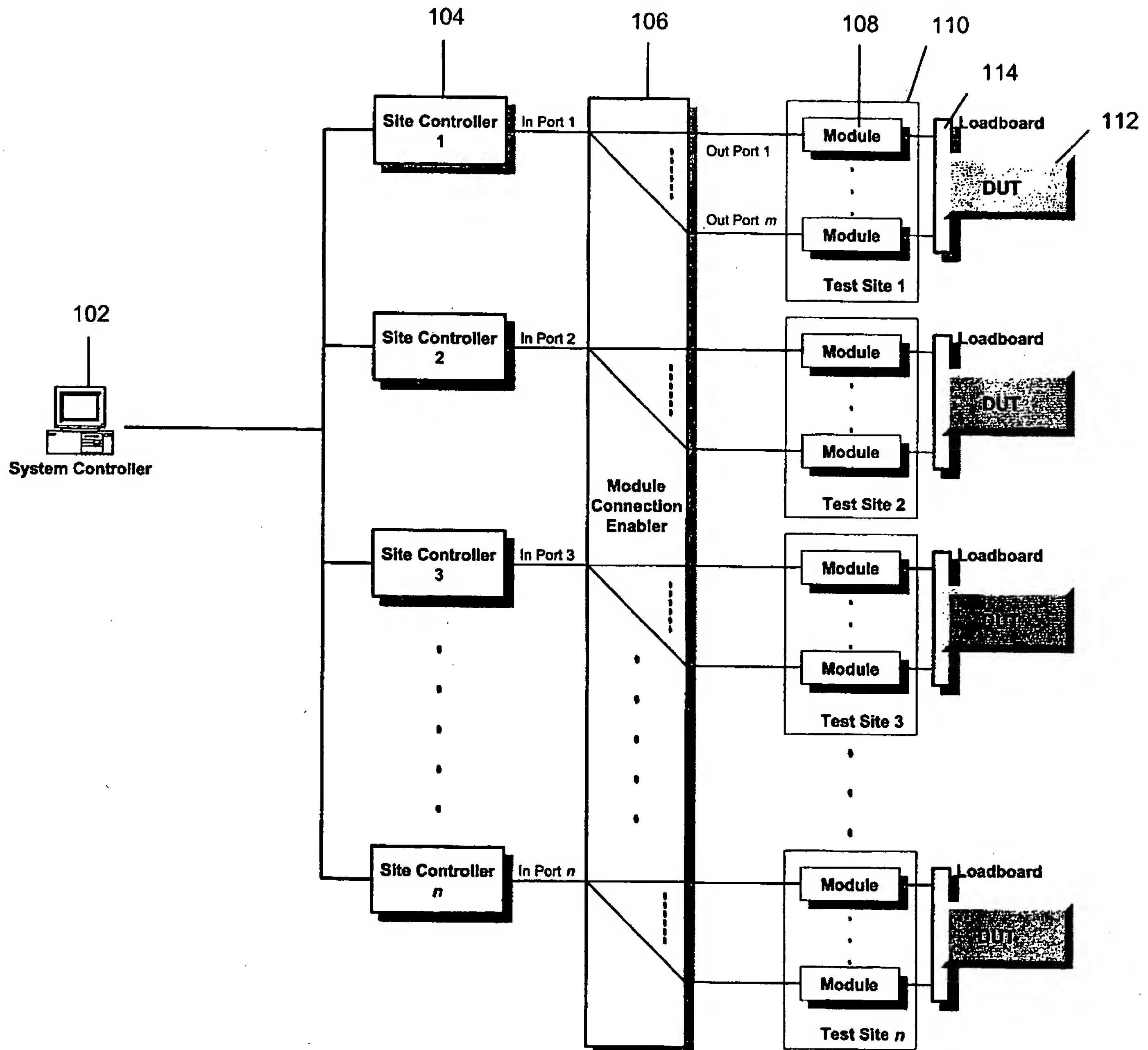


Figure 2

TEST AVAILABLE COPY

200

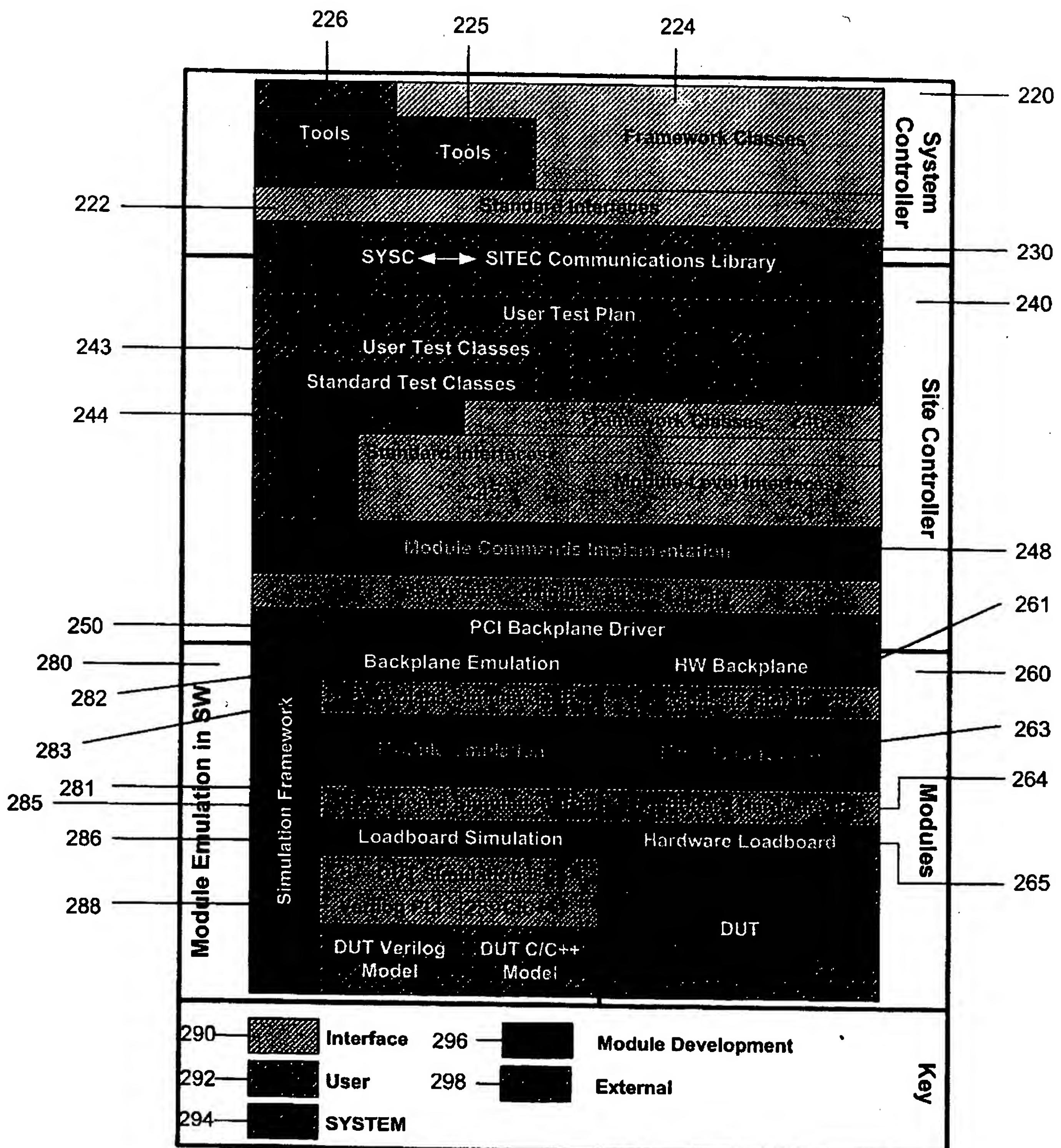


Figure 3

BEST AVAILABLE COPY

Title: METHOD AND STRUCTURE TO DEVELOP
A TEST PROGRAM FOR SEMICONDUCTOR
INTEGRATED CIRCUITS
Appn. No: Not Yet Assigned
Filed: Concurrently Herewith
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400

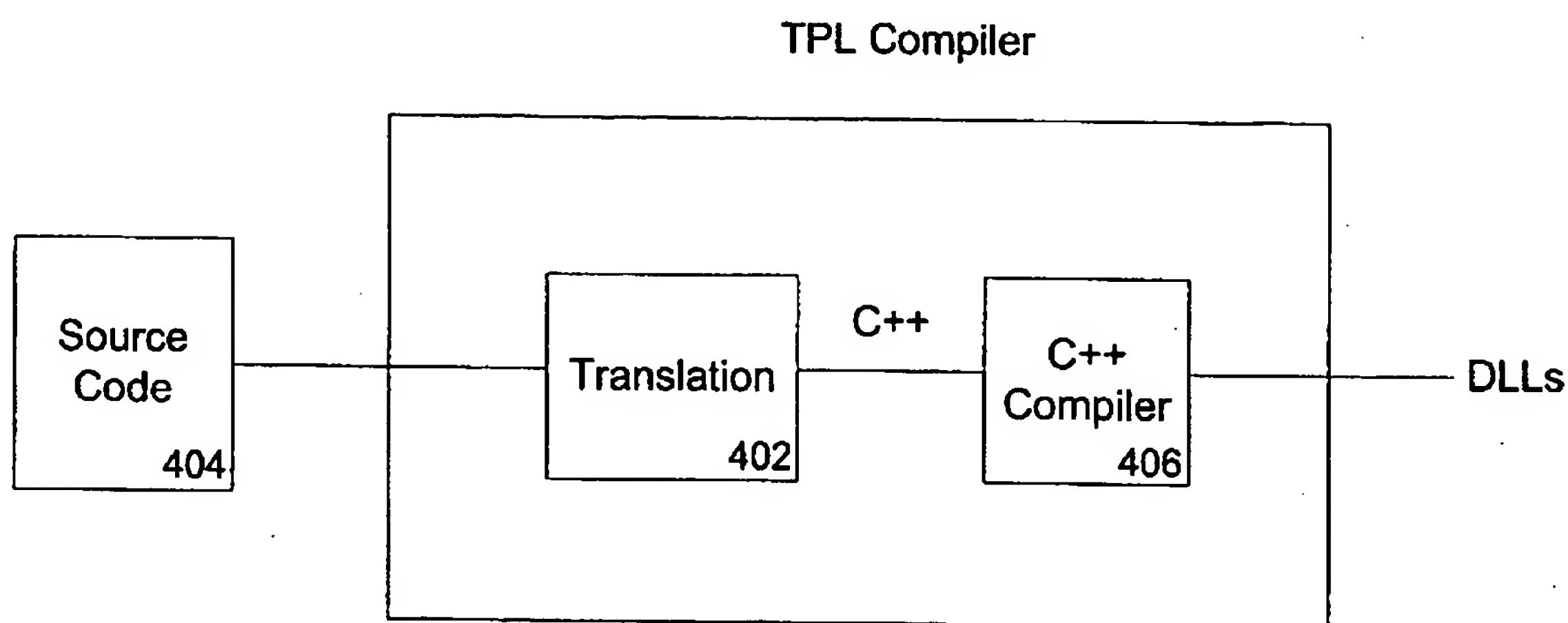


Figure 4

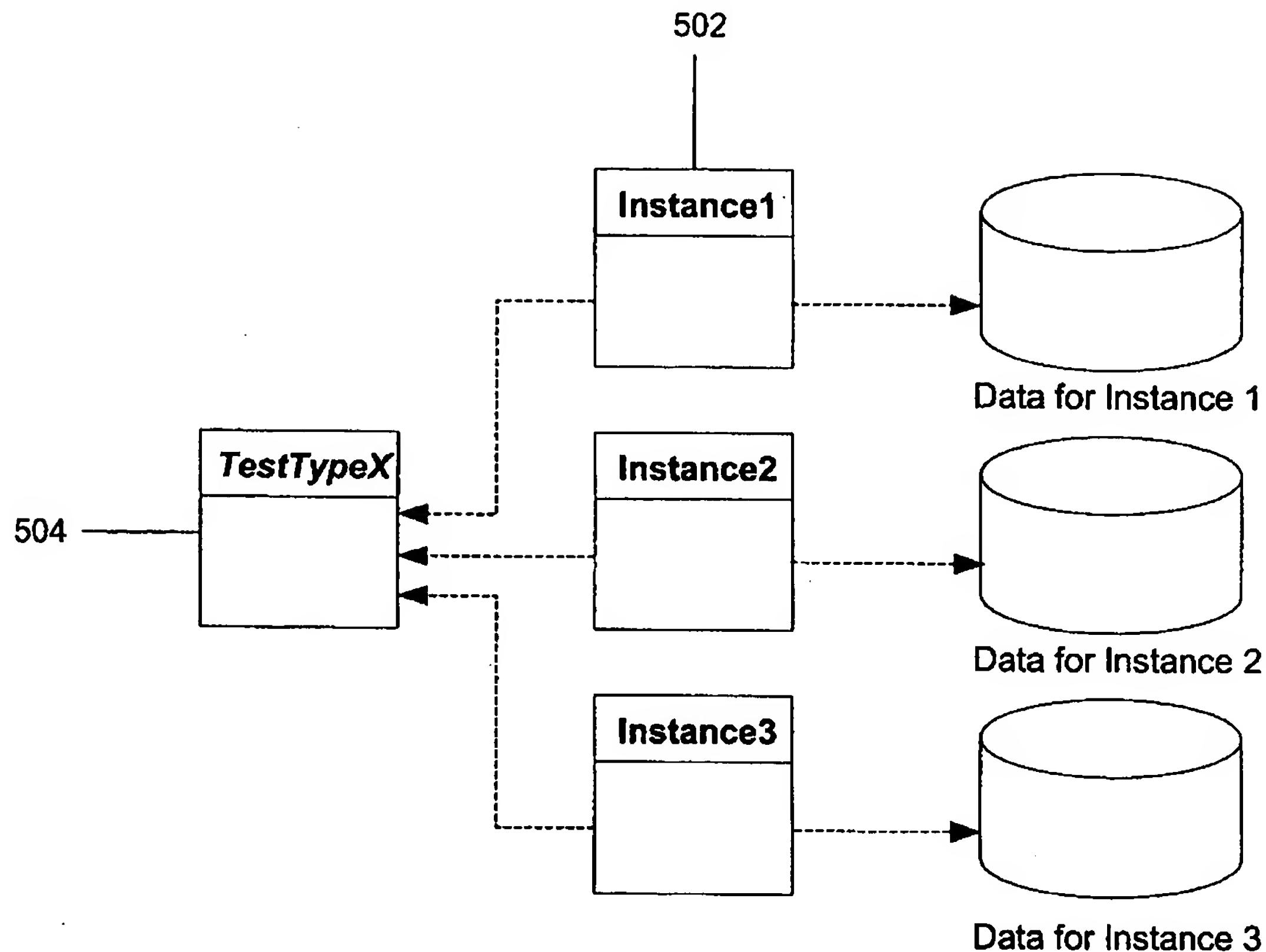


Figure 5

Title: METHOD AND STRUCTURE TO DEVELOP
A TEST PROGRAM FOR SEMICONDUCTOR
INTEGRATED CIRCUITS
Appn. No: Not Yet Assigned
Filed: Concurrently Herewith
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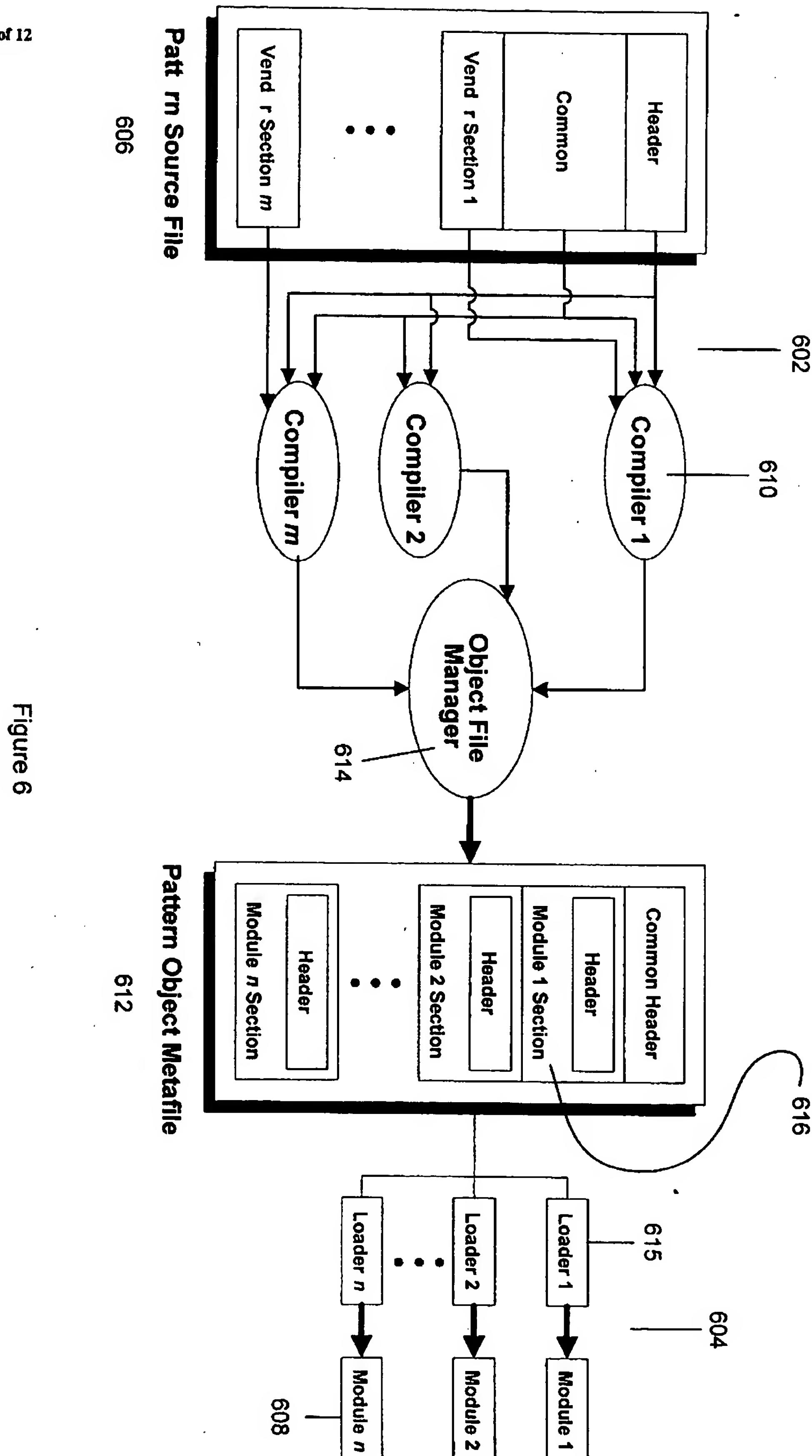


Figure 6

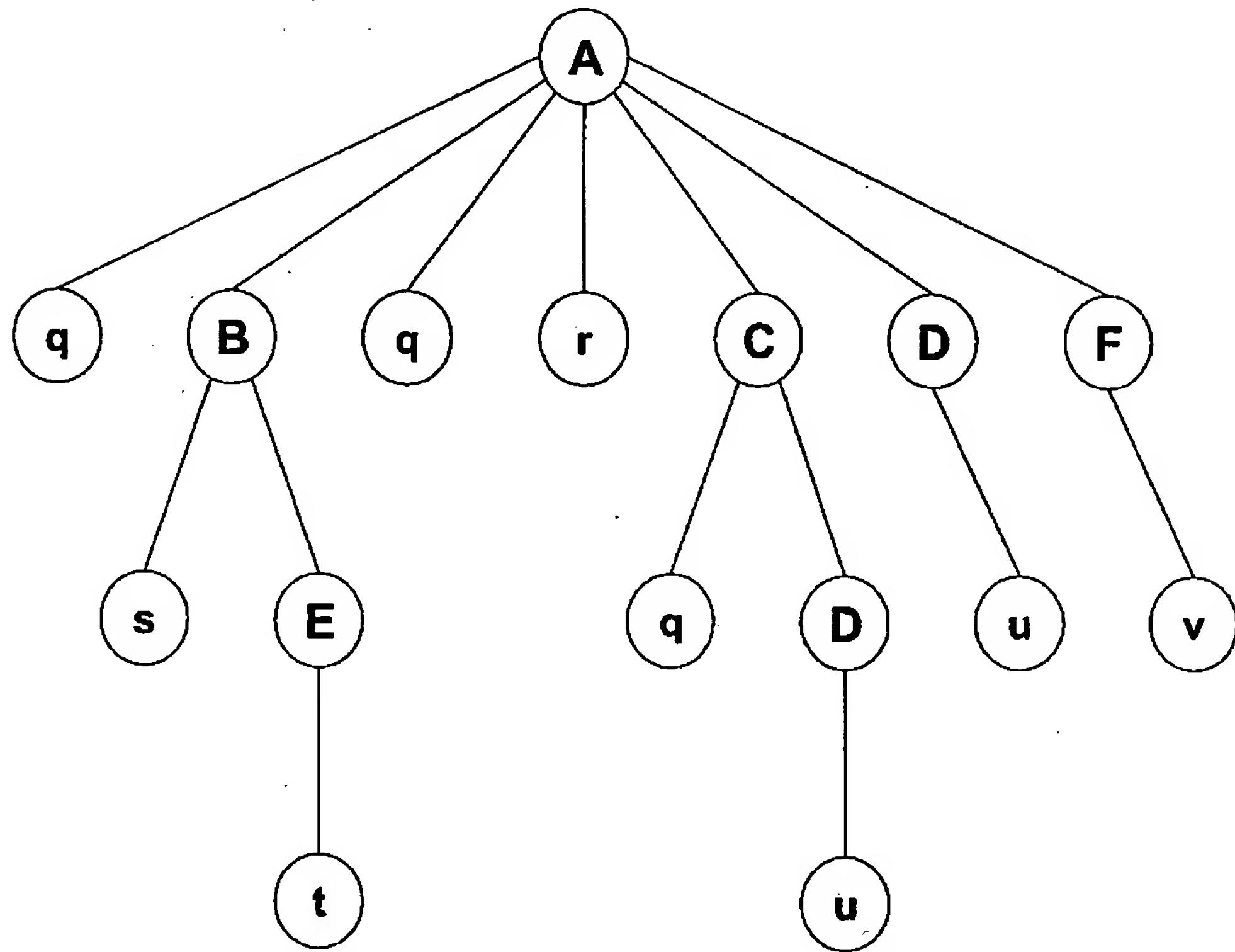


Figure 7

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INTEGRATED CIRCUITS
Appn. No: Not Yet Assigned
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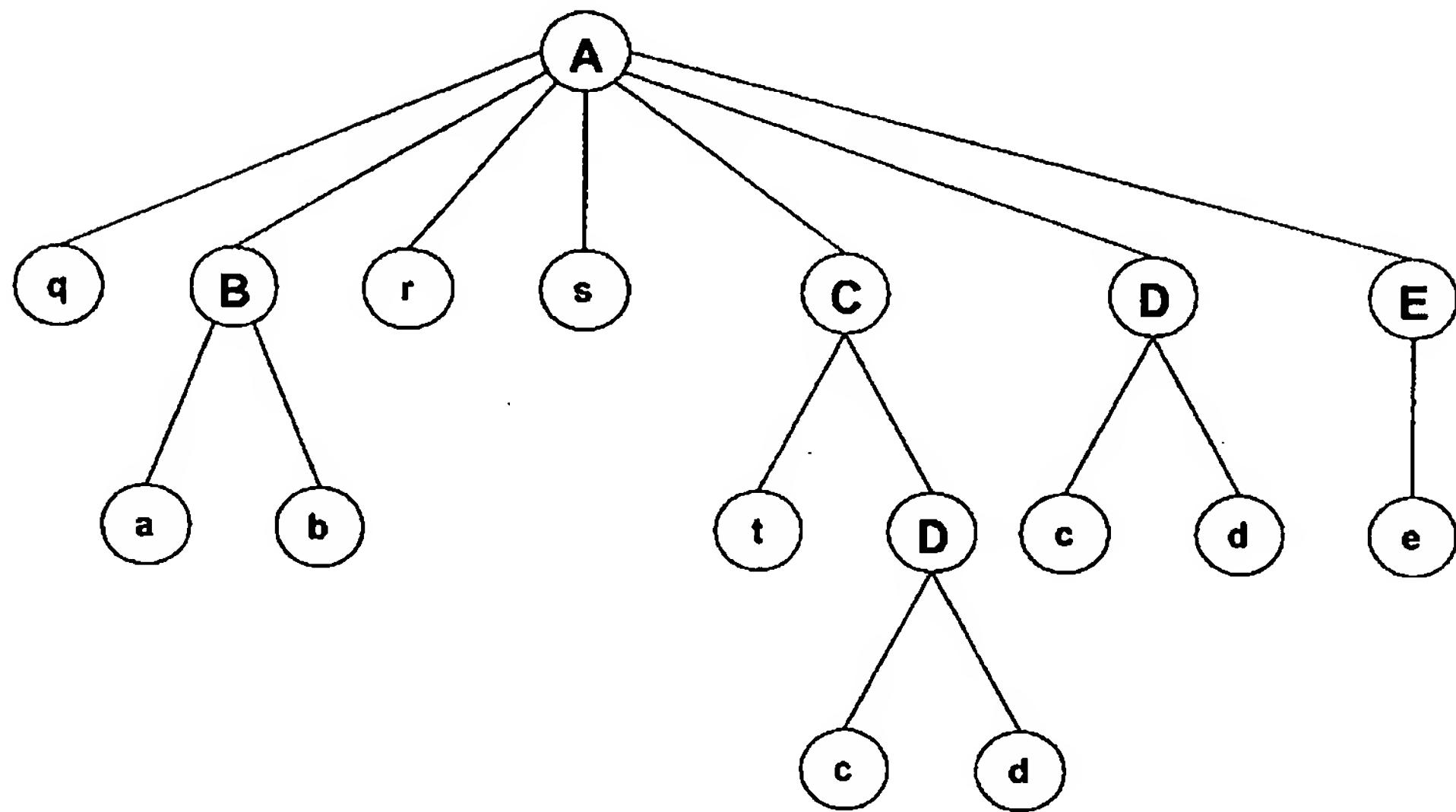


Figure 8

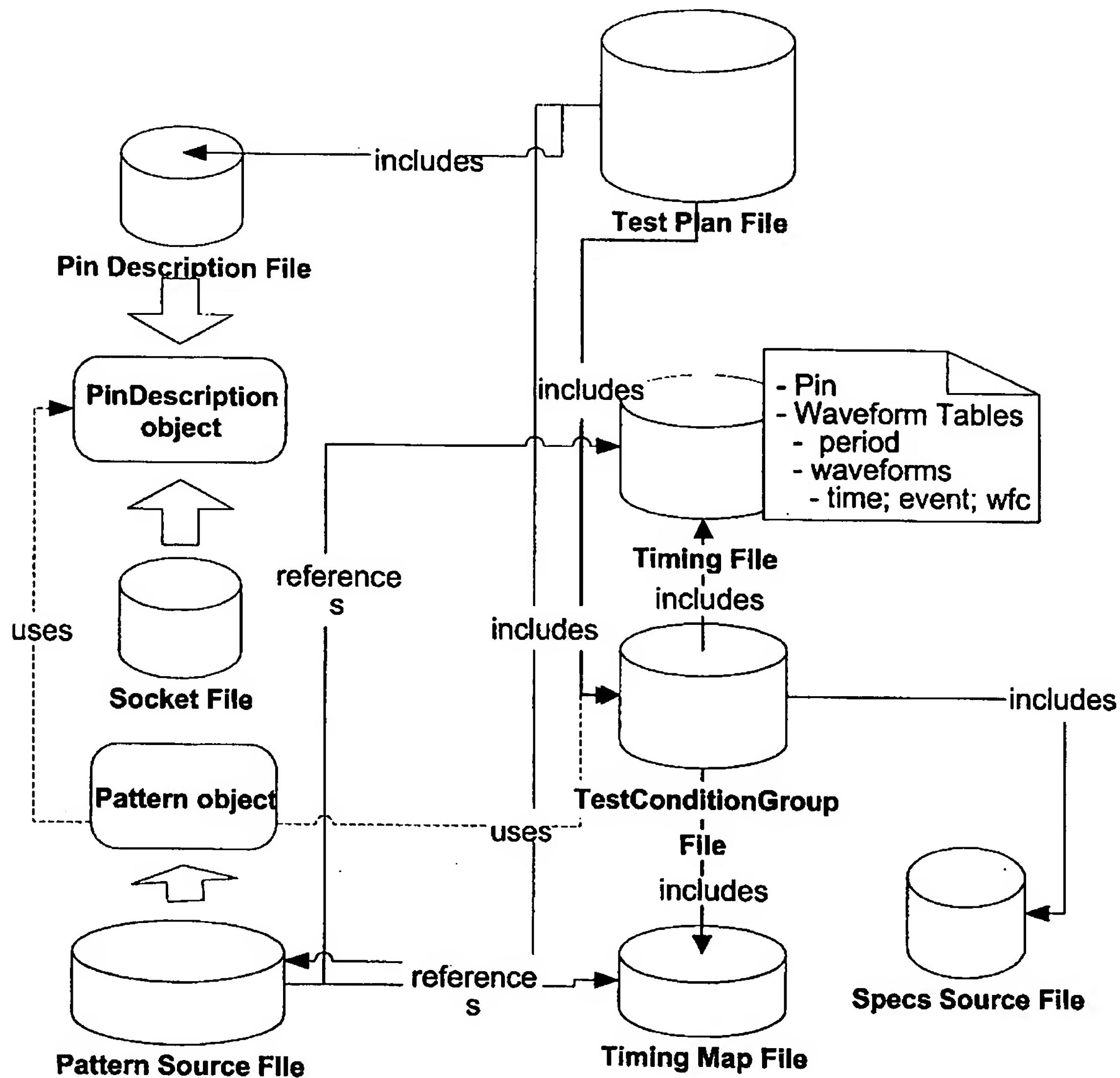


Figure 9

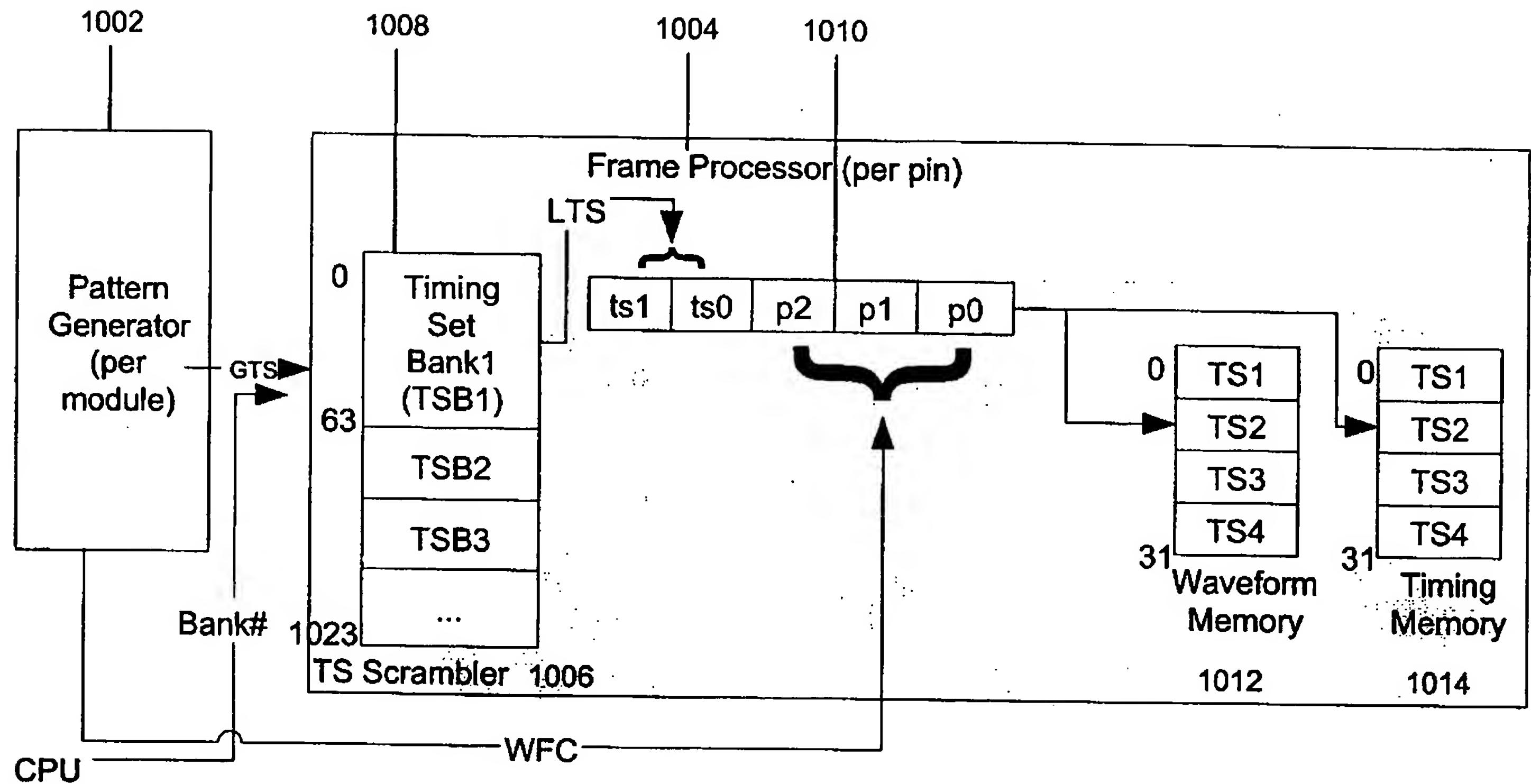


Figure 10

Title: METHOD AND STRUCTURE TO DEVELOP
A TEST PROGRAM FOR SEMICONDUCTOR
INTEGRATED CIRCUITS
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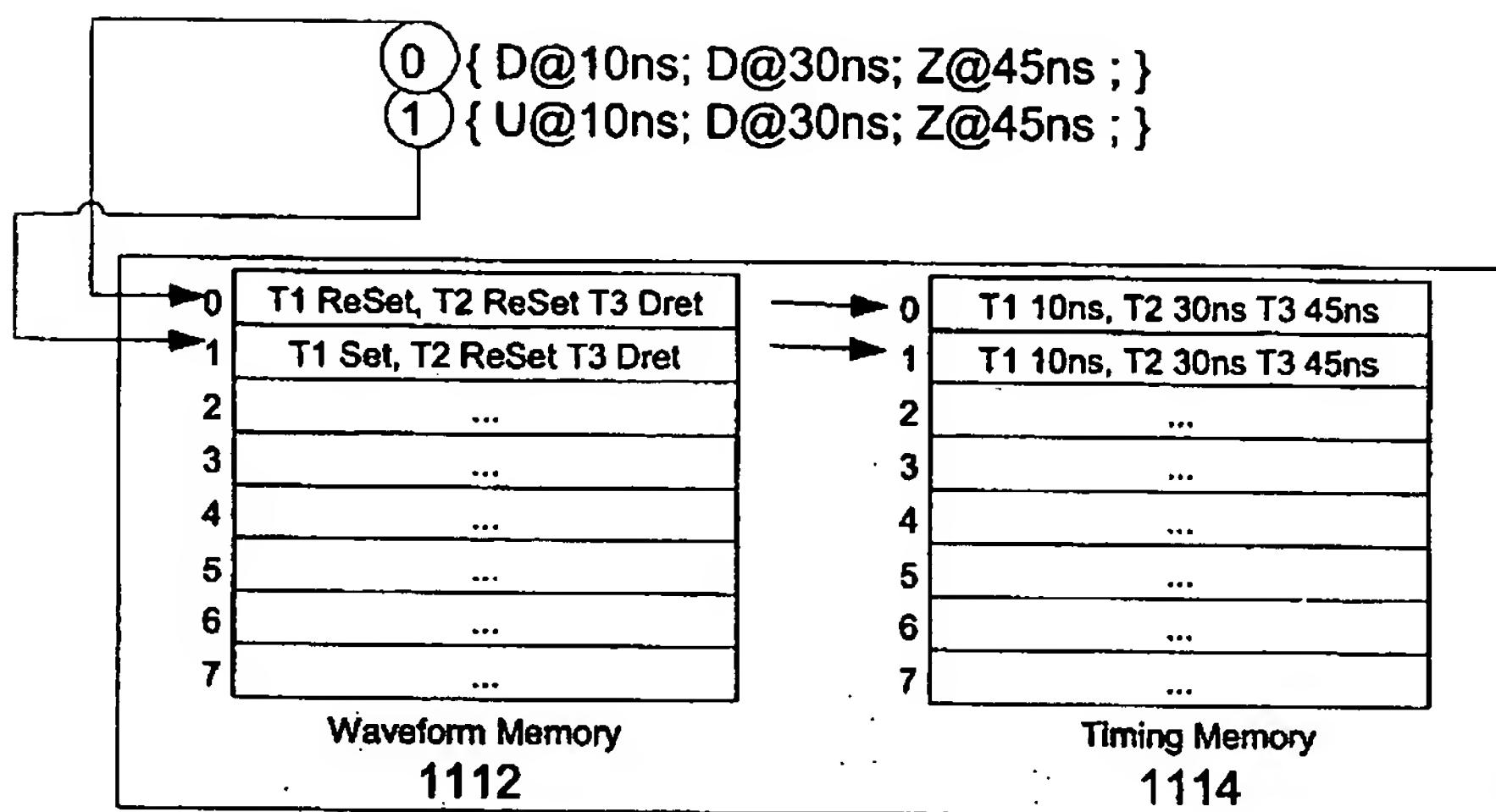


Figure 11

Title: METHOD AND STRUCTURE TO DEVELOP
A TEST PROGRAM FOR SEMICONDUCTOR
INTEGRATED CIRCUITS
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Docket No.: 333772000800 Sheet 12 of 12

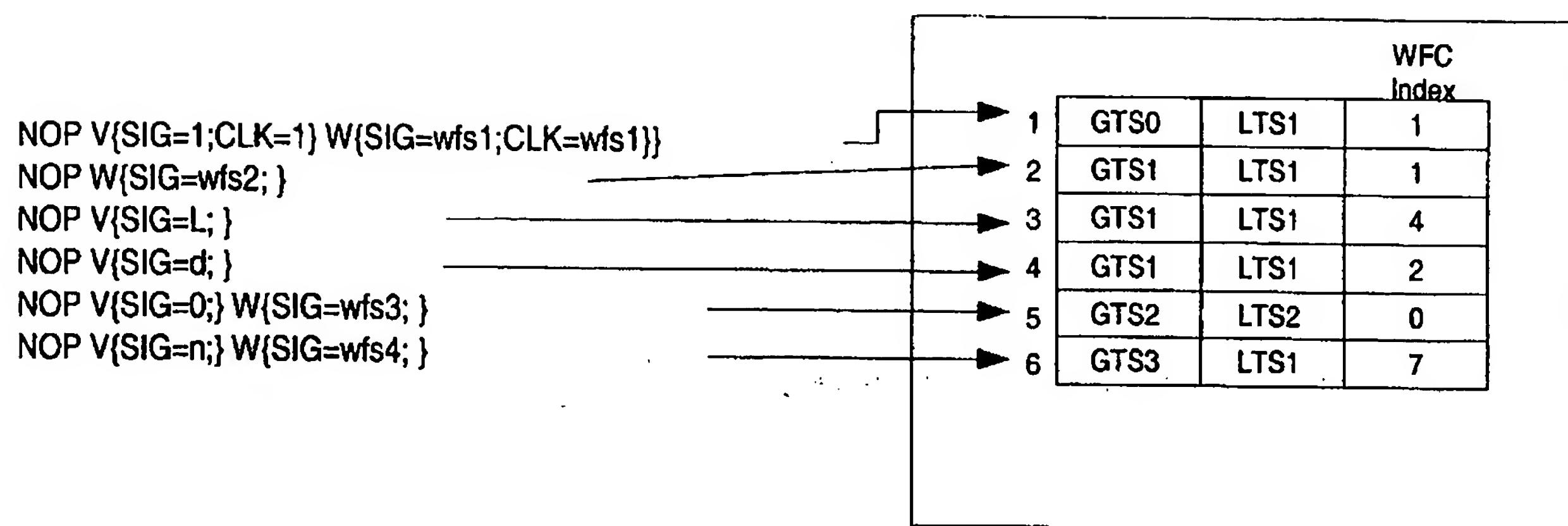


Figure 12